Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/618,157	VIGH ET AL.	
Examiner	Art Unit	
Matthew L. Fedowitz	1623	

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Class	Subclass	Date	Examiner
514	476	9/26/2005	MLF
514	507	9/26/2005	MLF
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